

<b>Notice of References Cited</b>	Application/Control No. 10/777,142	Applicant(s)/Patent Under Reexamination IDE ET AL.	
	Examiner Leith A. Al-Nazer	Art Unit 2821	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0033355	10-2001	Hagiwara, Takeshi	349/152
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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